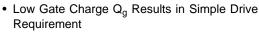


HM830I-VB Datasheet

N-Channel 650V (D-S) Super Junction Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	650				
$R_{DS(on)}(\Omega)$	V _{GS} = 10 V 0.95				
Q _g (Max.) (nC)	15				
Q _{gs} (nC)	3				
Q _{gd} (nC)	6				
Configuration	Single				

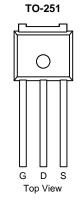
FEATURES

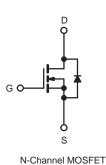




• Improved Gate, Avalanche and Dynamic dV/dt Ruggedness

- Fully Characterized Capacitance and Avalanche Voltage and Current
- Compliant to RoHS directive 2002/95/EC





ABSOLUTE MAXIMUM RATINGS $T_C = 25$ °C, unless otherwise noted					
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V _{DS}	650	V		
Gate-Source Voltage		V _{GS}	± 30	v	
Continuous Drain Current ^e	V_{GS} at 10 V $T_C = 25 ^{\circ}C$	1	5		
Continuous Drain Current	V_{GS} at 10 V $T_C = 100 ^{\circ}C$	I _D	4	A	
Pulsed Drain Current ^a	I _{DM}	16			
Linear Derating Factor		1.67/0.8/0.3	W/°C		
Single Pulse Avalanche Energy ^b	E _{AS}	120	mJ		
Repetitive Avalanche Current ^a	I _{AR}	34	А		
Repetitive Avalanche Energy ^a	E _{AR}	17	mJ		
Maximum Power Dissipation $T_C = 25 ^{\circ}C$		P_{D}	205/35/30	W	
Peak Diode Recovery dV/dtc	dV/dt	4.5	V/ns		
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C		
Soldering Recommendations (Peak Temperature) ^d for 10 s			300		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
Mounting Torque	0-32 OF IVIS SCIEW		1.1	N⋅m	

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Starting T $_J$ = 25 °C, L = 24 mH, R $_G$ = 25 Ω , I $_{AS}$ = 3.2 A (see fig. 12). c. I $_{SD} \le$ 3.2 A, dI/dt \le 90 A/ μ s, V $_{DD} \le$ V $_{DS}$, T $_J \le$ 150 °C.

- d. 1.6 mm from case.
- e. Drain current limited by maximum junction temperature.



THERMAL RESISTANCE RATINGS					
PARAMETER	SYMBOL	TYP.	MAX.	UNIT	
Maximum Junction-to-Ambient	R _{thJA}	-	62	°C/W	
Maximum Junction-to-Case (Drain)	R _{thJC}	-	3.6/1.2/0.6	C/VV	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} :	= 0 V, I _D = 250 μA	650	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Referenc	e to 25 °C, I _D = 1 mA ^d	-	0.6	-	mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μA	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	,	V _{GS} = ± 30 V		-	± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}		V _{DS} = 650 V, V _{GS} = 0 V V _{DS} = 520 V, V _{GS} = 0 V, T _J = 125 °C		-	10 100	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 2.5 A ^b	-	0.95	-	Ω
Forward Transconductance	9 _{fs}	V _{DS}	= 50 V, I _D = 2.5 A	8	-	-	S
Dynamic		1				l.	<u> </u>
Input Capacitance	C _{iss}		V _{GS} = 0 V,		320	-	
Output Capacitance	C _{oss}		$V_{DS} = 25 \text{ V},$	-	75	-	1
Reverse Transfer Capacitance	C _{rss}	f = 1	f = 1.0 MHz, see fig. 5		4	-	
Output Capacitance	C _{oss}		V _{DS} = 1.0 V, f = 1.0 MHz	-	500	-	pF
		$V_{GS} = 0 V$	V _{DS} = 520 V, f = 1.0 MHz	-	83	-	
Effective Output Capacitance	Coss eff.		V _{DS} = 0 V to 520 V ^c		14	-	
Total Gate Charge	Q_g		$V_{GS} = 10 \text{ V}$ $I_D = 2.5 \text{ A}, V_{DS} = 400 \text{ V}$ see fig. 6 and 13 ^b		-	15	nC
Gate-Source Charge	Q_{gs}	V _{GS} = 10 V			-	3	
Gate-Drain Charge	Q_{gd}				-	6	
Turn-On Delay Time	t _{d(on)}		1		18	-	
Rise Time	t _r		= 325 V, I _D = 3.2 A	-	40	-	1
Turn-Off Delay Time	t _{d(off)}	$R_{G} =$	$R_G = 9.1 \Omega, R_D = 62 \Omega,$ see fig. 10^b		50	-	ns -
Fall Time	t _f	1		-	30	-	
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	showing the	/		-	5	- A
Pulsed Diode Forward Current ^a	I _{SM}	p - n junction diode		-	-	16	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, I_S = 3.2 \text{A}, V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.5	V
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 3.2 A, dI/dt = 100 A/μs ^b		-	180	-	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	2.1	3.2	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L _S and L _D)				L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width \leq 300 µs; duty cycle \leq 2 %.
- c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 % to 80 % V_{DS} .
- d. t = 60 s, f = 60 Hz.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

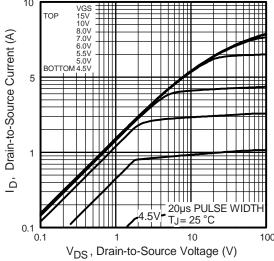


Fig. 1 - Typical Output Characteristics

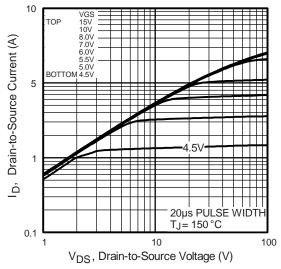


Fig. 2 - Typical Output Characteristics

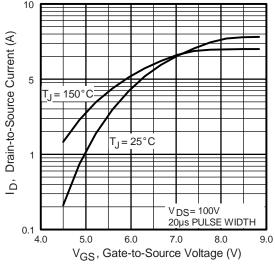


Fig. 3 - Typical Transfer Characteristics

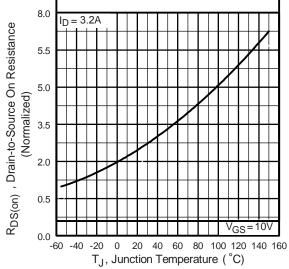


Fig. 4 - Normalized On-Resistance vs. Temperature



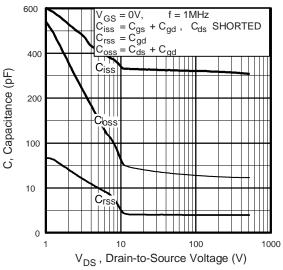


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

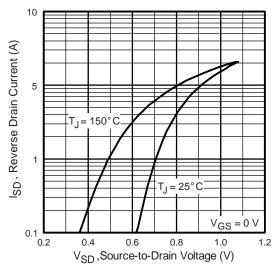


Fig. 7 - Typical Source-Drain Diode Forward Voltage

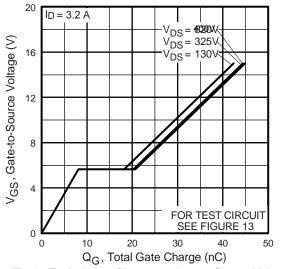


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

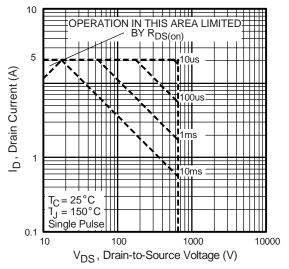


Fig. 8 - Maximum Safe Operating Area



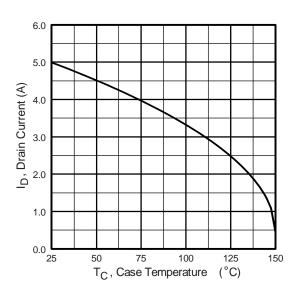


Fig. 9 - Maximum Drain Current vs. Case Temperature

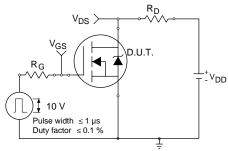


Fig. 10a - Switching Time Test Circuit

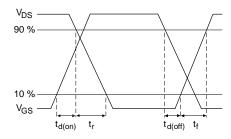


Fig. 10b - Switching Time Waveforms

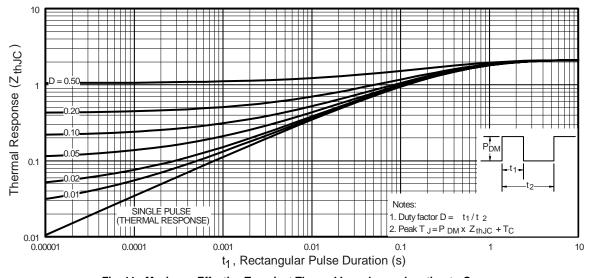


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

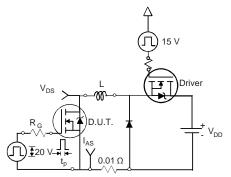


Fig. 12a - Unclamped Inductive Test Circuit

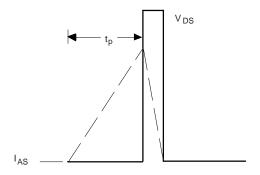


Fig. 12b - Unclamped Inductive Waveforms



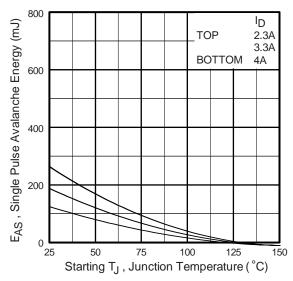


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

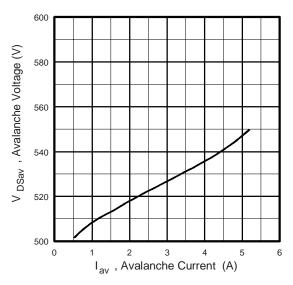


Fig. 12d - Typical Drain-to Source Voltage vs. Avalanche Current

6

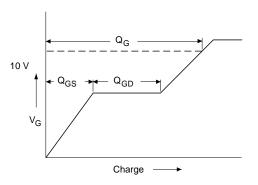


Fig. 13a - Basic Gate Charge Waveform

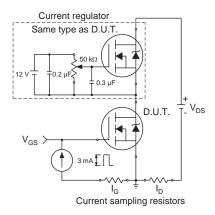
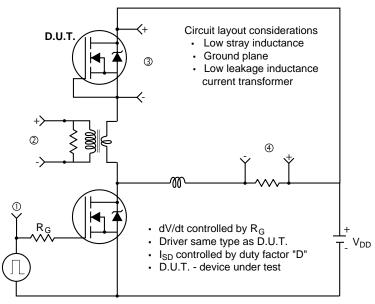


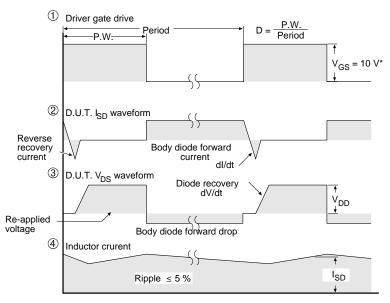
Fig. 13b - Gate Charge Test Circuit



7

Peak Diode Recovery dV/dt Test Circuit



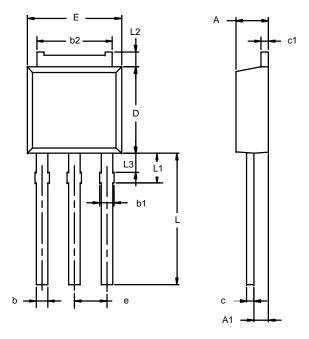


* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel



TO-251AA (DPAK)



Note: Dimension	L3 is for	reference only.
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	MILLIM	ETERS	INC	NCHES	
Dim	Min	Max	Min	Max	
Α	2.21	2.38	0.087	0.094	
A1	0.89	1.14	0.035	0.045	
b	0.71	0.89	0.028	0.035	
b1	0.76	1.14	0.030	0.045	
b2	5.23	5.43	0.206	0.214	
С	0.46	0.58	0.018	0.023	
с1	0.46	0.58	0.018	0.023	
D	5.97	6.22	0.235	0.245	
Е	6.48	6.73	0.255	0.265	
е	2.28 BSC		0.090	BSC	
L	8.89	9.53	0.350	0.375	
L1	1.91	2.28	0.075	0.090	
L2	0.89	1.27	0.035	0.050	
L3	1.15	1.52	0.045	0.060	
ECN: S-03946—Rev. E, 09-Jul-01 DWG: 5346					

DWG: 5346



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